



Einladung

zum

Seminar des Instituts für Quantenphysik

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High precision structured illumination microscopy

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Abstract: In optical microscopy, diffraction limits the precision with which we can localize an object. In this talk, I shall present a high-resolution method, the structured illumination microscopy (SIM) that has been of special interest in high precision imaging in recent years. Linear SIM was realized nearly 20 years ago but with resolution limitation. In this talk I shall discuss how high precision imaging can be achieved in linear SIM using surface plasmons. I shall also discuss a scheme based on Rabi oscillations.